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Terms	Documents
((test\$4 near circuit) near5 (embedded or included)) near10 (master)	0

Database:

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Search:

L6

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Hit Count Set Name
result set

DB=USPT; PLUR=YES; OP=OR

<u>L6</u>	((test\$4 near circuit) near5 (embedded or included)) near10 (master)	0	<u>L6</u>
<u>L5</u>	((test\$4 near circuit) near5 (embedded or included)) near10 (chip OR die OR IC)	40	<u>L5</u>
<u>L4</u>	L1 ((test\$4 near circuit) near5 (embedded or included)) near10 (chip OR die OR IC)	2706	<u>L4</u>
<u>L3</u>	(test\$4 near circuit) near10 (chip OR die OR IC)	1524	<u>L3</u>
<u>L2</u>	L1 (test\$4 near circuit) same (chip OR die OR IC)	2706	<u>L2</u>
<u>L1</u>	(test\$4 near circuit) same (chip OR die OR IC)	2706	<u>L1</u>

END OF SEARCH HISTORY